

**Notice of References Cited**

Application/Control No.

09/684,904

Applicant(s)/Patent Under

Reexamination

KON ET AL.

Examiner

THANH V TRAN

Art Unit

2814

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**U.S. PATENT DOCUMENTS**

*		Document Number		Date	Name	Classification	
		Country Code-Number-Kind Code					
	A	US-5,874,750		02-1999	Yanagisawa et al.	257	133
	B	US-					
	C	US-					
	D	US-					
	E	US-					
	F	US-					
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